

# EAST Search History

10/805,670

| Ref # | Hits | Search Query   | DBs   | Default Operator | Plurals | Time Stamp       |
|-------|------|--|---|------------------|---------|------------------|
| L1    | 1    | 10/805670  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | OFF     | 2006/09/23 18:01 |
| L2    | 2    | ("5952692").PN.  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | OFF     | 2006/09/23 19:01 |
| L3    | 2    | ("5973356").PN.  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | OFF     | 2006/09/23 18:01 |
| L4    | 4    | ("6211531").PN.  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | OFF     | 2006/09/23 19:02 |
| L5    | 4    | semiconductor adj memory adj<br>element adj arrangement  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | OFF     | 2006/09/23 18:03 |
| L6    | 4    | 5 and (first or second or elctrically or<br>insulating or substrate or electrode or<br>trench or structure or arranged or<br>parallel or structures or gate or<br>polysilicon or nitride or oxide or silicon<br>or elctrical or charge or floating or<br>multiple or photolithography or<br>trenches or pattern or opening or<br>openings or size or feature or width or<br>read or control or voltage or reading<br>or controlling) | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | OFF     | 2006/09/23 18:14 |

## EAST Search History

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| L7  | 2 | 2 and (first or second or elctrically or insulating or substrate or electrode or trench or structure or arranged or parallel or structures or gate or polysilicon or nitride or oxide or silicon or elctrical or charge or floating or multiple or photolithography or trenches or pattern or opening or openings or size or feature or width or read or control or voltage or reading or controlling) | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | OFF | 2006/09/23 18:44 |
| L8  | 2 | 3 and (first or second or elctrically or insulating or substrate or electrode or trench or structure or arranged or parallel or structures or gate or polysilicon or nitride or oxide or silicon or elctrical or charge or floating or multiple or photolithography or trenches or pattern or opening or openings or size or feature or width or read or control or voltage or reading or controlling) | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | OFF | 2006/09/23 18:40 |
| L9  | 1 | "5705415".PN.  | USPAT;<br>USOCR   | OR | OFF | 2006/09/23 18:34 |
| L10 | 1 | "5691230".PN.  | USPAT;<br>USOCR   | OR | OFF | 2006/09/23 18:34 |
| L11 | 1 | "5646900".PN.  | USPAT;<br>USOCR   | OR | OFF | 2006/09/23 18:35 |
| L12 | 1 | "5644540".PN.  | USPAT;<br>USOCR   | OR | OFF | 2006/09/23 18:35 |
| L13 | 1 | "5640342".PN.  | USPAT;<br>USOCR   | OR | OFF | 2006/09/23 18:35 |
| L14 | 1 | "5616934".PN.  | USPAT;<br>USOCR   | OR | OFF | 2006/09/23 18:35 |
| L15 | 1 | "5593912".PN.  | USPAT;<br>USOCR   | OR | OFF | 2006/09/23 18:36 |
| L16 | 1 | "5574299".PN.  | USPAT;<br>USOCR   | OR | OFF | 2006/09/23 18:37 |
| L17 | 1 | "5497017".PN.  | USPAT;<br>USOCR   | OR | OFF | 2006/09/23 18:38 |
| L18 | 1 | "5504357".PN.  | USPAT;<br>USOCR   | OR | OFF | 2006/09/23 18:39 |
| L19 | 1 | "5497017".PN.  | USPAT;<br>USOCR   | OR | OFF | 2006/09/23 18:39 |

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|-----|------|---|---|----|-----|------------------|
| L20 | 4    | 4 and (first or second or elctrically or insulating or substrate or electrode or trench or structure or arranged or parallel or structures or gate or polysilicon or nitride or oxide or silicon or elctrical or charge or floating or multiple or photolithography or trenches or pattern or opening or openings or size or feature or width or read or control or voltage or reading or controlling)  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | OFF | 2006/09/23 18:40 |
| L21 | 1    | "5604357".PN.   | USPAT;<br>USOCR   | OR | OFF | 2006/09/23 18:42 |
| L22 | 1    | "5319229".PN.   | USPAT;<br>USOCR   | OR | OFF | 2006/09/23 18:42 |
| L23 | 1    | "5286994".PN.   | USPAT;<br>USOCR   | OR | OFF | 2006/09/23 18:43 |
| L24 | 1    | "5216262".PN.   | USPAT;<br>USOCR   | OR | OFF | 2006/09/23 18:44 |
| L25 | 1    | 23 and (first or second or elctrically or insulating or substrate or electrode or trench or structure or arranged or parallel or structures or gate or polysilicon or nitride or oxide or silicon or elctrical or charge or floating or multiple or photolithography or trenches or pattern or opening or openings or size or feature or width or read or control or voltage or reading or controlling) | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | OFF | 2006/09/23 18:46 |
| L26 | 1    | 19 and (first or second or elctrically or insulating or substrate or electrode or trench or structure or arranged or parallel or structures or gate or polysilicon or nitride or oxide or silicon or elctrical or charge or floating or multiple or photolithography or trenches or pattern or opening or openings or size or feature or width or read or control or voltage or reading or controlling) | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | OFF | 2006/09/23 18:46 |
| L27 | 4158 | 438/257   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | OFF | 2006/09/23 19:03 |

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|     |      |         |   |    |     |                  |
|-----|------|---------|---|----|-----|------------------|
| L28 | 692  | 438/263 | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | OFF | 2006/09/23 19:03 |
| L29 | 1711 | 438/264 | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | OFF | 2006/09/23 19:03 |
| L30 | 1077 | 438/266 | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | OFF | 2006/09/23 19:03 |
| L31 | 1500 | 438/270 | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | OFF | 2006/09/23 19:03 |
| L32 | 2905 | 438/238 | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | OFF | 2006/09/23 19:03 |
| L33 | 1680 | 438/381 | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | OFF | 2006/09/23 19:03 |
| L34 | 1677 | 438/680 | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | OFF | 2006/09/23 19:03 |
| L35 | 4719 | 438/692 | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | OFF | 2006/09/23 19:03 |

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|     |      |         |   |    |     |                  |
|-----|------|---------|---|----|-----|------------------|
| L36 | 2849 | 438/706 | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | OFF | 2006/09/23 19:04 |
| L37 | 1866 | 438/723 | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | OFF | 2006/09/23 19:04 |
| L38 | 1060 | 438/724 | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | OFF | 2006/09/23 19:04 |
| L39 | 723  | 438/743 | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | OFF | 2006/09/23 19:04 |
| L40 | 463  | 438/744 | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | OFF | 2006/09/23 19:04 |
| L41 | 2071 | 438/700 | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | OFF | 2006/09/23 19:04 |